



UNISONIC TECHNOLOGIES CO., LTD

2N7002ZT

Power MOSFET

300mA, 60V N-CHANNEL
ENHANCEMENT MODE POWER
MOSFET

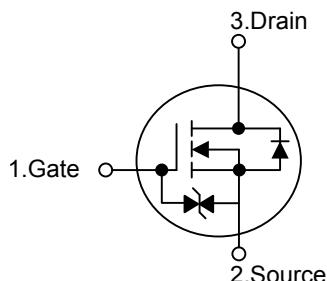
■ DESCRIPTION

The UTC **2N7002ZT** uses advanced technology to provide excellent $R_{DS(ON)}$, low gate charge and low gate voltages during operation. This device is suitable for use as a load switch or in PWM applications.

■ FEATURES

- * Low Reverse Transfer Capacitance (C_{RSS} = typical 3.0 pF)
- * ESD Protected
- * Fast Switching Capability
- * Avalanche Energy Specified
- * Improved dv/dt Capability, High Ruggedness

■ SYMBOL



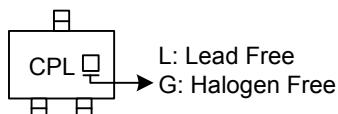
■ ORDERING INFORMATION

Ordering Number		Package	Pin Assignment			Packing
Lead Free	Halogen Free		1	2	3	
2N7002ZTL-AN3-R	2N7002ZTG-AN3-R	SOT-523	G	S	D	Tape Reel

Note: Pin Assignment: G: Gate S: Source D: Drain

	(1)Packing Type (2)Package Type (3)Green Package	(1) R: Tape Reel (2) AN3: SOT-523 (3) G: Halogen Free and Lead Free, L: Lead Free
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■ MARKING



■ ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$, unless otherwise specified.)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	60	V
Gate-Source Voltage		V_{GSS}	± 20	V
Drain Current	Continuous	I_D	300	mA
	Pulse(Note 2)		800	
Power Dissipation		P_D	200	mW
Derating above $T_A=25^\circ\text{C}$			1.6	mW/ $^\circ\text{C}$
Junction Temperature		T_J	+150	$^\circ\text{C}$
Storage Temperature		T_{STG}	-55 ~ +150	$^\circ\text{C}$

Note: Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

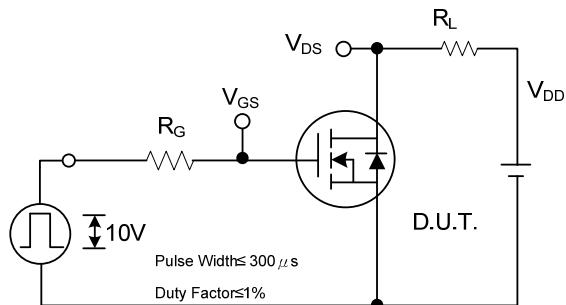
■ ELECTRICAL CHARACTERISTICS ($T_A=25^\circ\text{C}$, unless otherwise specified.)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS}=0\text{V}, I_D=10\mu\text{A}$	60			V
Drain-Source Leakage Current	I_{DSS}	$V_{DS}=60\text{V}, V_{GS}=0\text{V}$			1	μA
Gate-Source Leakage Current	I_{GSS}	$V_{DS}=0\text{V}, V_{GS}=\pm 20\text{V}$			± 10	μA
ON CHARACTERISTICS						
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS}=10\text{V}, I_D=1\text{mA}$	1.0	1.85	2.5	V
Static Drain-Source On-Resistance (Note)	$R_{DS(ON)}$	$V_{GS}=10\text{V}, I_D=0.3\text{A}, T_J=125^\circ\text{C}$			13.5	Ω
		$V_{GS}=5\text{V}, I_D=0.05\text{A}$			7.5	
DYNAMIC PARAMETERS						
Input Capacitance	C_{ISS}	$V_{DS}=25\text{V}, V_{GS}=0\text{V}, f=1.0\text{MHz}$		25	50	pF
Output Capacitance	C_{OSS}			10	25	pF
Reverse Transfer Capacitance	C_{RSS}			3.0	5.0	pF
SWITCHING PARAMETERS						
Turn-ON Delay Time	$t_{D(ON)}$	$I_D=0.2 \text{ A}, V_{DD}=30\text{V}, V_{GS}=10\text{V}, R_L=150\Omega, R_G=10\Omega$		12	20	ns
Turn-OFF Delay Time	$t_{D(OFF)}$			20	30	ns
DRAIN-SOURCE DIODE CHARACTERISTICS AND MAXIMUM RATINGS						
Maximum Continuous Drain-Source Diode Forward Current	I_S				300	mA
Maximum Pulsed Drain-Source Diode Forward Current	I_{SM}				0.8	A
Drain-Source Diode Forward Voltage	V_{SD}	$V_{GS}=0\text{V}, I_S=300\text{mA}$ (Note)		0.88	1.5	V

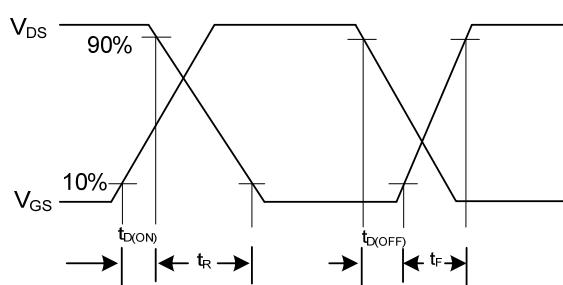
Notes: 1. Device mounted on FR-4 PCB, 1 inch x 0.85 inch x 0.062 inch. Minimum land pad size.

2. Pulse width $\leq 300\mu\text{s}$, Duty cycle $\leq 1\%$

■ TEST CIRCUITS AND WAVEFORMS



Switching Test Circuit



Switching Waveforms

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